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Spontaneous emission from active dielectric microstructures

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Published in: 2000 International Quantum Electronics Conference Digest

Link to article, DOI: 10.1109/IQEC.2000.908170

Publication date: 2001

Document Version Publisher's PDF, also known as Version of record

Link back to DTU Orbit

Citation (APA): Søndergaard, T., & Tromborg, B. (2001). Spontaneous emission from active dielectric microstructures. In 2000 International Quantum Electronics Conference Digest (pp. 224-224). Nice, France. DOI: 10.1109/IQEC.2000.908170

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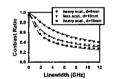
Variable coherence in determining the scattering parameters of diffuse media using laser speckle

K.J. Wohb, M.A. Webster, J.D. McKit upper and A.M. Weiner School of Sectrical and Computer Engineering, Pardue University, West Interpretent Information (INV):1383, ISSA Phi: 1-716-543-5437 (arX8), Ima: 1-765-541-7518, arX845.

We demonstrate the application of a variable coherence laser source for determining the scattering parameters of a diffuse medium and the potential for imaging spatially-dependent scatter. A key concept in this work is the ability to synthesize a variable-coherence source by frequency medulating a tunable laser diffect (with a conter wavelength of 860 nm) at a vate much faster than the integration time of the detector. This allows for a rapid measurement and the adaption of laser coherence to the degree of scatter, which we show is critical in obtaining the necessary semilivity

In transmiss an interview statistic arc described by the contrast ratio, which we have previously shown can be used to extract material parameters using light of fixed coherence by varying the material thickness [1]. The experiments used commercially available white excitors (with the scattering due to ~50 nm TO), particles asspended in the acrylic background) as the diffuse modium in a transmission geometry. The speckle contrast ratio dependence upon the source linevidth was measured, with the results above: in Fig. 1. The theoretical fits were obtained using an approximate Green's function for the diffusion equation.

ma were obtained using an approximate Green's function for the dimusion equation. To demonstrate sensitivity of the specific contrast ratio to exciting variations, we have performed a number of experiments to collect imaging-type data [2]. This data shows a spatially-varying contrast ratio which can be used to reconstruct photon transit time distributions. In the images of Fig. 2, the difference of contrast ratio between the inhomogeneous and homogeneous cases is shown Lighter shades represent a higher contrast than in the homogeneous and homogeneous cases is shown Lighter shades represent a higher contrast excito ettered in the inhomogeneous and homogeneous cases is shown Lighter shades represent a higher contrast aregins of higher contrast ratio corresponding to the localized reduction of scattering introduced by a wolf Conversely, in Fig. 2(d), one can see a region of lower contrast ratio the to healized increase in scattering increase the swith a scriptic inhomogeneity. No localization of the inhomogeneities is observed for the 5 MHz linewidth used in Figs. 2(a) and 2(c), demonstrating the importance of the source coherence.



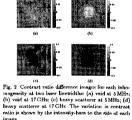


Fig. 1. Contrast ratio data as a function of laser linewidth for two different arryline. The symbols are car-perimented data, and the dathed lines are linearistical fits. The top and botton curves are for the heavily scat-tering, arryline with $\mu_{ij}'=12$ Gam⁻¹. The middle curve is for the fease archieving acrylic with $\mu_{ij}'=6$ cm⁻¹. The she bit bit sets is elah thirkowee is d

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0-7803-6318-3/00/\$10.00@2000 IEEE

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Spontaneous emission from active dielectric microstructures. Thomas Søndergaard and Bjarne Tromborg

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taneous emission is one of the key factors that determine the noise properties of photonic Spontaneous emission is one of the key factors that determine the noise properties of photoaus devices and the pump power threshold of lasers. The spontaneous emission in dielectric microstructures (micro-cavities, photonic crystals, optical waveguides, etc.) can to some extend be controlled and engineered due to the dependence of the emission rate on the location and polarisation of the emitters in the structure [1,2]. This paper addresses the methods of quantum electrodynamics of dielectric media which enable calculation of the local rate of spontaneous emission in active microstructures.

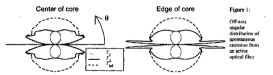
rate of spontaneous emission in active microstructures. For passive structures the spontaneous emission may be derived by expanding the radiation field in power-orthogonal modes normalized to one quantum of energy, and using the Fermi Golden Rule. This approach was used in [1] for calculating the position dependence of spontaneous emission in passive photonic crystals. However, for active materials the mode concept is problematic, and it is more convenient to express observable quantities in terms of the field operators and generating currents. The total rate of spontaneous emission is given by 240

 $\Gamma = \frac{2\mu_0}{4} \operatorname{Im}\left(\int \langle \vec{j}^*(\vec{r}') \cdot \vec{G}(\vec{r}',\vec{r}') \cdot \vec{j}(\vec{r}') \rangle d^3 \vec{r}' d^3 \vec{r}''\right)$ (1)

where $\bar{j}(\bar{r})$ is the generating current, and $\bar{G}(\bar{r}', \bar{r}')$ is the classical transverse Green's tensor that determines the electric field in terms of the transverse current. For materials with gain the tensor can be derived from the solutions to the homogeneous wave equation and the adjoint wave equation

wave equation. As an example we show in Figure 1, in polar coordinates, the distribution of spontaneous emission going into radiation modes from an active optical fiber. The distributions are shown for the emitter in the center of the fiber core and at the edge of the fiber core, respectively. The optical fiber has the core refractive index 1.45, cladding refractive index 1.43, core radius 2 μ m. The emission wavelength is 1508 nm. The emission rate Γ_r is for dipoles with orientation along the fiber axis, Γ_{\perp} is the sum of emission rates for dipoles with orientation perpendicular to the fiber axis, and Γ_{in} is the sum of these two emission rates.

The presentation will include an analysis of the effects of gain on the radiation pattern and the ratio of radiation into the guided mode(s) for active optical fibers.



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